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# Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China







# **Dual-Channel USB Host Adapter Emulators**

### **General Description**

The MAX14657/MAX14658/MAX14659 are next-generation dual-channel USB 2.0 host-charger adapter emulators that combine USB Hi-Speed analog switches with a USB adapter emulator circuit.

The MAX14657 features an I $^2$ C interface to fully configure the charging behavior with different address options. The MAX14658/MAX14659 are controlled by two GPIO inputs (CB1\_/CB0\_) and support USB data and automatic charger mode. In charging downstream port (CDP) mode, the devices emulate the CDP function while supporting normal USB traffic. The MAX14657/MAX14658 have a CEN\_ output for an active-high CLS enable input, and the MAX14659 has a  $\overline{\text{CEN}}$ \_ output for an active-low CLS enable input to restart the peripheral connected to the USB host.

The MAX14658/MAX14659 feature 2A high-current autodetect mode. The MAX14657 can be configured through I<sup>2</sup>C to support various dedicated charger modes such as Apple 1A/2A forced, or Apple or Samsung 1A/2A autodetect modes.

The MAX14657/MAX14658/MAX14659 support CDP and standard downstream port (SDP) charging while in the active state (S0), and support the dedicated charging port (DCP) charging while in the standby state (S3/S4/S5). All of the devices support low-speed remote wake-up by monitoring DM\_, and also support remote wakeup in sleep mode (S3).

The MAX14657/MAX14658/MAX14659 are available in a 16-pin (3mm x 3mm) TQFN-EP package and are specified over the -40°C to +85°C extended temperature range.

### **Applications**

- Laptop/Desktop Computers
- USB Hubs
- Universal Chargers Including iPod®/iPhone®/iPad®

iPod®/iPhone®/iPad® are registered trademarks of Apple, Inc <u>Ordering Information</u> and <u>Typical Operating Circuit</u> appear at end of data sheet.

For related parts and recommended products to use with this part, refer to <a href="https://www.maximintegrated.com/MAX14657.related">www.maximintegrated.com/MAX14657.related</a>.

### **Benefits and Features**

- Integrated Dual Channels
  - More Convenient, High-Current USB Charging Ports for Users
  - · Simple and Flexible Power-Management Control
  - · Small TQFN Package Minimizes PCB Area
- Improved Charger Interoperability
  - USB (CDP) Emulation with Smart CDP and Fool-Proof CDP
  - · Enhanced Automodes
  - · Foolproof CDP
  - Meets New USB Battery Charging (BC) Revision 1.2 Specification
  - Backward Compatible with Previous USB BC Revisions
  - Meets China YD/T1591-2009 Charging Specification
  - Supports Standby-Mode Charging for USB BC Revision 1.2 Compatible Devices
- Provide Greater Application Flexibility
  - I<sup>2</sup>C Controls Multiple Modes (MAX14657)
  - A Slave Address Selection Input Offers Two Possible Slave Addresses for Each Emulator (MAX14657)
  - CB0\_ and CB1\_ Pins Control Multiple Automatic and Manual Charger States (MAX14658, MAX14659)
- Enhance Performance with High Level of Integrated Features
  - Supports Remote Wake-Up
  - Low-Capacitance USB 2.0 Hi-Speed Switch to Change Charging Modes
  - · Automatic Current-Limit Switch Control
  - ±15kV ESD Protection on DP\_/DM\_

### **Selector Guide**

PART NUMBER	I/O MODE	CEN POLARITY	REMOTE WAKE-UP IN AM	
MAX14657	I <sup>2</sup> C	Programmable (CEN default)	Programmable	
MAX14658	GPIO	CEN	Yes	
MAX14659	GPIO	CEN	Yes	



# **Dual-Channel USB Host Adapter Emulators**

### **Absolute Maximum Ratings**

(All voltages referenced to GND.)	Operating Temperature Range	40°C to +85°C
V <sub>CC</sub> , TDP_, TDM_, DP_, DM_, SDA,	Junction Temperature	
SCL, CB0_, CB1_, CEN_, CEN_, SAS, INT0.3V to +6V	Storage Temperature Range	65°C to +150°C
Continuous Current into Any Terminal±30mA	Lead Temperature (soldering, 10s)	+300°C
Continuous Power Dissipation (T <sub>A</sub> = +70°C)	Soldering Temperature (reflow)	
TOFN (derate 20.8mW/°C above +70°C) 1666 7mW	3 - 1 - 1 - 1	

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

### **Package Thermal Characteristics (Note 1)**

#### TOFN

Junction-to-Ambient Thermal Resistance ( $\theta_{JA}$ ).......48°C/W Junction-to-Case Thermal Resistance ( $\theta_{JC}$ ).......10°C/W

Note 1: Package thermal resistances were obtained using the method described in JEDEC specification JESD51-7, using a four-layer board. For detailed information on package thermal considerations, refer to www.maximintegrated.com/thermal-tutorial.

### **Electrical Characteristics**

 $(V_{CC} = 3.0 \text{V to } 5.5 \text{V}, T_A = -40 ^{\circ}\text{C} \text{ to } +85 ^{\circ}\text{C}, \text{ unless otherwise noted.}$  Typical values are at  $V_{CC} = +5.0 \text{V}$  and  $T_A = +25 ^{\circ}\text{C}$ .) (Note 2)

PARAMETER	SYMBOL		MIN	TYP	MAX	UNITS	
POWER SUPPLY	•						
		MAX14658 MAX14659	CB0_ = high/CB1_ = low (PM mode) CB0_ = low/CB1_ = high (FM mode)	2.0			
		MAX14657	MODE_SEL[2:0] = 001 (PM mode) MODE_SEL[2:0] = 010 (FM mode)	3.0		5.5	V
V <sub>CC</sub> Supply Voltage		MAX14658 MAX14659	CB0_ = low/CB1_ = low (AM2 mode) CB0_ = high/CB1_ = high (CM mode) (Note 3)	4.75		5.25	
		MAX14657	MODE_SEL[2:0] = XXX except: MODE_SEL[2:0] = 001 (PM mode) MODE_SEL[2:0] = 010 (FM mode) (Note 3)				

# **Electrical Characteristics (continued)**

 $(V_{CC} = 3.0V \text{ to } 5.5V, T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}, \text{ unless otherwise noted.}$  Typical values are at  $V_{CC} = +5.0V \text{ and } T_A = +25^{\circ}\text{C.})$  (Note 2)

PARAMETER	SYMBOL		CONDITIONS	MIN	TYP	MAX	UNITS
			CB1_ = CB0_ = low (AM2 mode)			120	
		MAX14658 MAX14659	CB1_ = CB0_ = high (CM mode)			150	
V Supply Current	la a		CB1_ = low/CB0_ = high (PM mode)			25	
V <sub>CC</sub> Supply Current	ICC		MODE_SEL[2:0] = 000 (AM2 mode)			120	μA
		MAX14657	MODE_SEL[2:0] = 011 (CM mode)			150	
			MODE_SEL[2:0] = 001 (PM mode)			25	
POR Delay	t <sub>POR</sub>				50		ms
ANALOG SWITCHES (DP_, DM	_, TDP_, TDM_)						
Analog Signal Range	V <sub>DP</sub> , V <sub>DM</sub>	(Note 4)		0		V <sub>CC</sub>	V
TDP_/TDM_ On-Resistance	R <sub>ON</sub>	V <sub>CC</sub> = 3V, V	' <sub>IN</sub> = 0V, V <sub>CC</sub> , I <sub>IN</sub> = 10mA		3.5	6.5	Ω
TDP_/TDM_ On-Resistance Matching Between Channels	ΔR <sub>ON</sub>	V <sub>CC</sub> = 3V, V	V <sub>CC</sub> = 3V, V <sub>IN</sub> = 0V, V <sub>CC</sub> , I <sub>IN</sub> = 10mA		0.1		Ω
TDP_/TDM_ On-Resistance Flatness	R <sub>FLAT</sub>	V <sub>CC</sub> = 3V, V <sub>IN</sub> = 0V, V <sub>CC</sub> , I <sub>IN</sub> = 10mA			0.1		Ω
DP_/DM_ Short On-Resistance	R <sub>SHORT</sub>	$V_{DP}$ = 1V, $R_L$ = 20k $\Omega$ on DM_			70	130	Ω
Off-Leakage Current	I <sub>COM(OFF)</sub>		V <sub>DP</sub> = V <sub>DM</sub> = 0.3V, 3.3V; <sub>DM</sub> _ = 0.3V, 3.3V	-1000		+1000	nA
On-Leakage Current	I <sub>COM(ON)</sub>	V <sub>CC</sub> = 3.6V,	V <sub>DP</sub> _ = V <sub>DM</sub> _ = 0.3V, 3.3V	-1000	90	+1000	nA
DYNAMIC PERFORMANCE							
Turn-On Time	t <sub>ON</sub>	$V_{TDP}$ or $V_{T}$ $C_{L} = 35pF, F$	$_{\text{TDM}}$ = 1.5V, R <sub>L</sub> = 300Ω, Figure 1		10		μs
Turn-Off Time	t <sub>OFF</sub>	$V_{TDP}$ or $V_{TE}$ $C_L = 35pF$ , F	$_{\rm DM}$ = 1.5V, R <sub>L</sub> = 300Ω, =igure 1		10		μs
TDP_/TDM_ Propagation Delay	t <sub>PHL</sub> , t <sub>PLH</sub>		0Ω, DP_ and DM_ connected d TDM_, Figure 2		60		ps
DP_/DM_ Output Skew	tskew		0Ω, DP_ and DM_ connected d TDM_, Figure 2		40		ps
DP_/DM On-Capacitance (Connected to TDP_, TDM_)	C <sub>ON</sub>	f = 240MHz, V <sub>BIAS</sub> = 0V, V <sub>IN</sub> = 500mV <sub>P-P</sub>			5		pF
Bandwidth	BW	$R_L = R_S = 50Ω$ , Figure 3			1000		MHz
Off-Isolation	V <sub>ISO</sub>	$V_{IN}$ = 0dBm, $R_L$ = $R_S$ = 50 $\Omega$ , f = 250MHz, Figure 3			-20		dB
Crosstalk	V <sub>CT</sub>	V <sub>IN</sub> = 0dBm Figure 3	, $R_L = R_S = 50Ω$ , $f = 250MHz$ ,		-25		dB

# **Electrical Characteristics (continued)**

 $(V_{CC} = 3.0V \text{ to } 5.5V, T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}, \text{ unless otherwise noted.}$  Typical values are at  $V_{CC} = +5.0V \text{ and } T_A = +25^{\circ}\text{C.})$  (Note 2)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
DCP BIAS VOLTAGES AND IN	TERNAL RESISTO	DRS (Note 3)				
DP_/DM_ Short Pulldown	R <sub>PD</sub>		320	500	700	kΩ
40%V <sub>CC</sub> Bias	V <sub>AP1A(2A)_P(M)</sub>		39	40	41	%V <sub>CC</sub>
40%V <sub>CC</sub> Bias Source Impedance	R <sub>AP1A(2A)_</sub> P(M)		21	30	39	kΩ
53.6%V <sub>CC</sub> Bias	V <sub>AP1A(2A)_M(P)</sub>		52.6	53.6	54.6	%V <sub>CC</sub>
53.6%V <sub>CC</sub> Bias Source Impedance	R <sub>AP1A(2A)_M(P)</sub>		16.24	23.2	30.16	kΩ
25%V <sub>CC</sub> Bias	V <sub>SSG_P/M</sub>		24	25	26	%V <sub>CC</sub>
25%V <sub>CC</sub> Bias Source Impedance	R <sub>SSG_P/M</sub>		5.25	7.5	9.75	kΩ
CDP INTERNAL RESISTORS						
DP Pulldown Resistor	R <sub>DP_CDP</sub>	CDP mode	14.25	19.53	24.80	kΩ
DM Pulldown Resistor	R <sub>DM_CDP</sub>	CDP mode	14.25	19.53	24.80	kΩ
CDP HIGH-SPEED COMPARAT	ORS (Note 3)					
Detection Threshold Voltage	V <sub>TH_CDP</sub>		100	161	205	mV
CDP LOW-SPEED COMPARAT	ORS (Note 3)					
V <sub>DM_SRC</sub> Voltage	V <sub>DM_SRC</sub>	I <sub>LOAD</sub> = 0, 200μA	0.5		0.7	V
V <sub>DP_REF</sub> Voltage	V <sub>DP_REF</sub>		0.25		0.4	V
V <sub>LGC</sub> Voltage	V <sub>LGC</sub>		0.8		2.0	V
I <sub>DP_SINK</sub> Current	I <sub>DP_SINK</sub>	V <sub>DP</sub> = 0.15V, 3.6V	50		150	μA
LOGIC INPUTS (CB0_, CB1_, S	SDA, SCL, SAS)					
Input Logic High Voltage	V <sub>IH</sub>		1.4			V
Input Logic Low Voltage	V <sub>IL</sub>				0.4	V
Input Leakage Current	I <sub>IN</sub>	$V_{CC}$ = 5.5V; $V_{IN}$ = 0V, $V_{CC}$	-1		+1	μA
CB0_/CB1_ Debounce Time	t <sub>DEB_CB_</sub>			250		μs
OPEN-DRAIN LOGIC OUTPUT	S (SDA, INT, CEN	_, CEN_)				
INT, SDA, CEN_ Output Low Voltage	V <sub>OL</sub>	Output asserted, I <sub>SINK</sub> = 4mA			0.4	V
INT, SDA, CEN_ Output Leakage Current	ГОН	Output not asserted, V <sub>CC</sub> = V <sub>OUT</sub> = 5.5V			1	μΑ
CEN_ Output High Voltage	V <sub>OH</sub>	Output asserted, I <sub>SOURCE</sub> = 4mA	V <sub>CC</sub> - 0.4			V
CEN_ Output Leakage Current	l <sub>OL</sub>	Output not asserted, V <sub>CC</sub> = 5.5V, V <sub>CEN</sub> = 0V			1	μA
V <sub>BUS</sub> Toggle Time Accuracy	t <sub>VBT</sub>	-		±10		%

### **Electrical Characteristics (continued)**

 $(V_{CC} = 3.0V \text{ to } 5.5V, T_A = -40^{\circ}\text{C} \text{ to } +85^{\circ}\text{C}, \text{ unless otherwise noted.}$  Typical values are at  $V_{CC} = +5.0V \text{ and } T_A = +25^{\circ}\text{C}.)$  (Note 2)

PARAMETER	SYMBOL	COND	MIN	TYP	MAX	UNITS			
I <sup>2</sup> C TIMING CHARACTERISTICS (SEE FIGURE 4)									
I <sup>2</sup> C Maximum Clock Frequency	f <sub>SCL</sub>					400	kHz		
ESD PROTECTION									
ESD Protection	V	Human Bady Madal	DP_ and DM_ pins		±15		kV		
ESD Protection	$V_{ESD}$	Human Body Model	All other pins		±2		] KV		

- Note 2: All units are production tested at T<sub>A</sub> = +25°C. Specifications over temperature are guaranteed by design.
- Note 3: The devices are operational from 3.0V to 5.5V. However, in order for the valid Apple/Samsung resistor-divider networks to function and to have the required DCP/CDP parameters accuracy, V<sub>CC</sub> must stay within the 4.75V to 5.25V range.
- Note 4: Guaranteed by design, not production tested.

### **Test Circuits/Timing Diagrams**

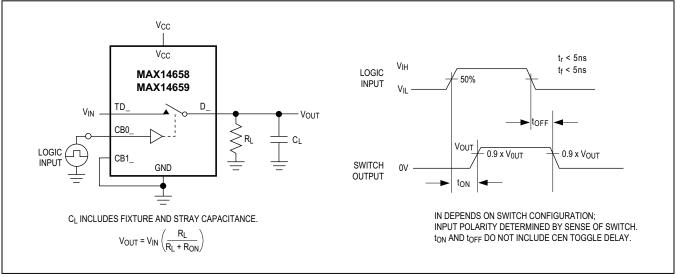


Figure 1. Switching Time

# **Test Circuits/Timing Diagrams (continued)**

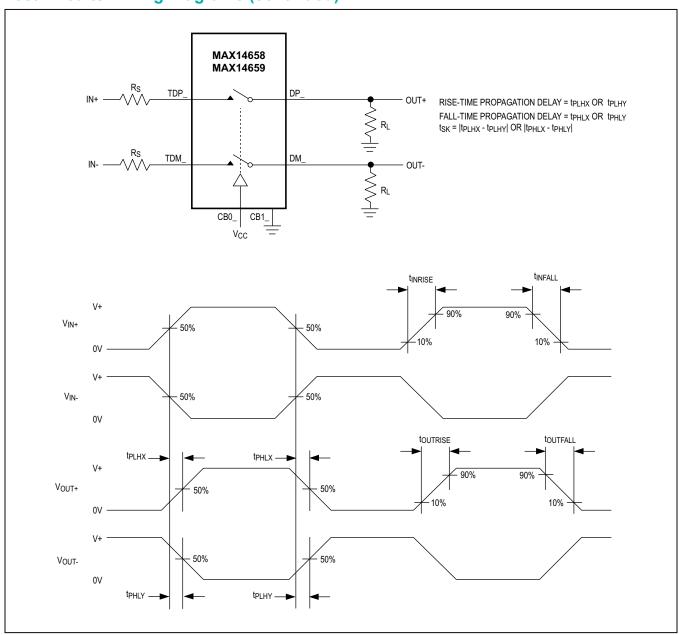


Figure 2. Propagation Delay and Output Skew

# **Test Circuits/Timing Diagrams (continued)**

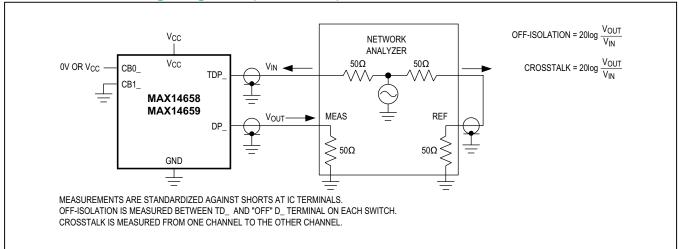


Figure 3. Bandwidth, Off-Isolation, and Crosstalk

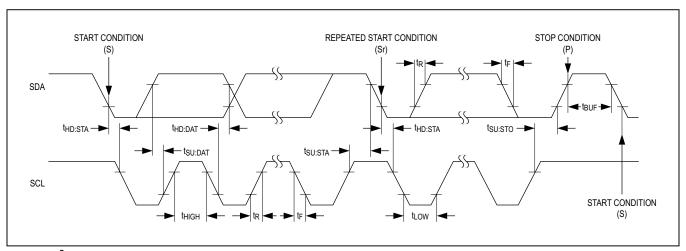
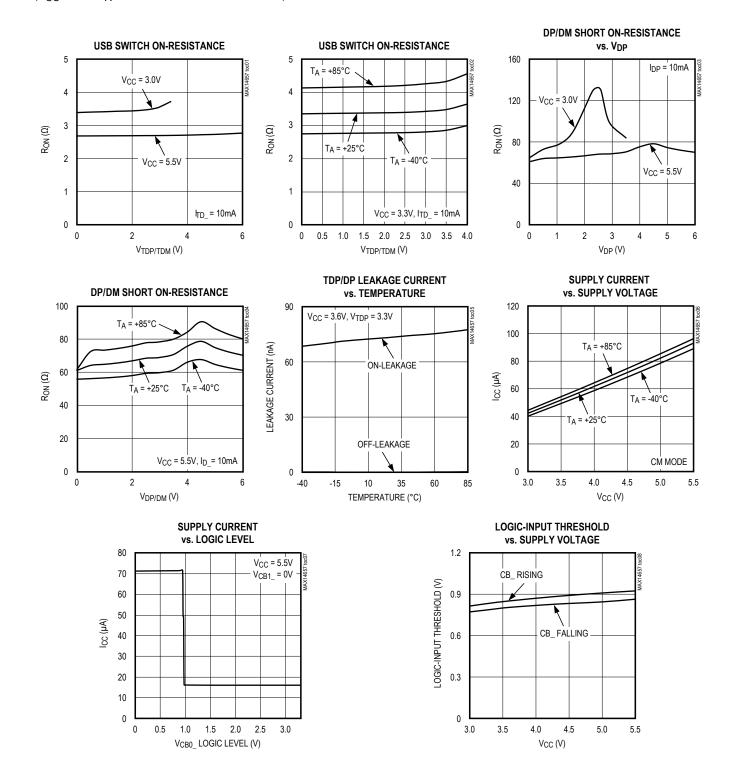


Figure 4. I<sup>2</sup>C Timing Diagram

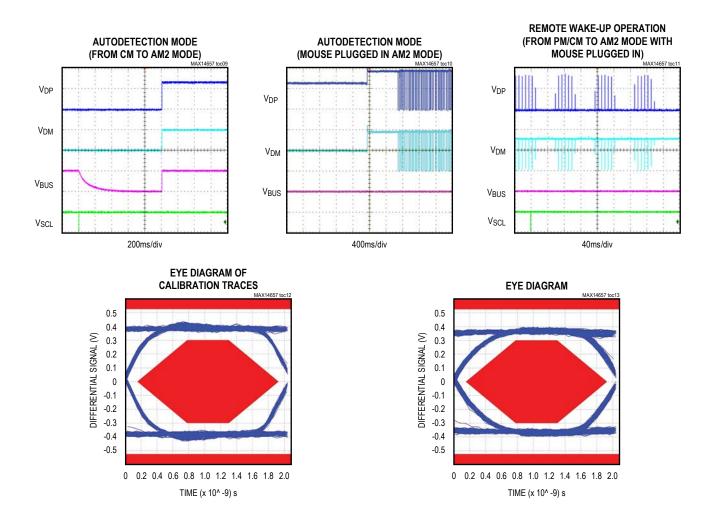
# **Typical Operating Characteristics**

( $V_{CC}$  = +5V,  $T_A$  = +25°C, unless otherwise noted.)

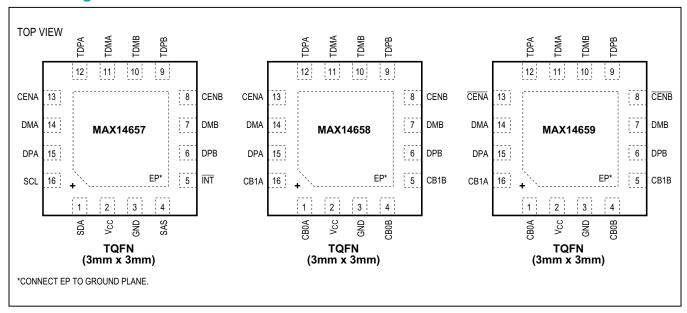


# **Typical Operating Characteristics (continued)**

(TA = +25°C, unless otherwise noted.)



# **Pin Configurations**



# **Pin Descriptions**

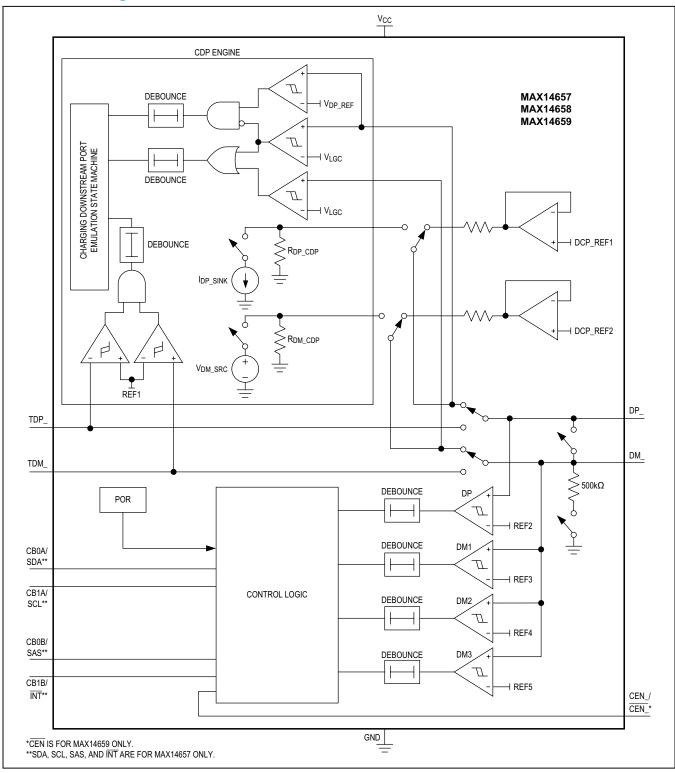
	PIN		PIN		NAME	FUNCTION
MAX14657	MAX14658	MAX14659	NAME	FUNCTION		
1	_	_	SDA	I <sup>2</sup> C Serial Data		
_	1	1	CB0A	Switch Control Bit. See the switch control input table 1.		
2	2	2	V <sub>CC</sub>	Power Supply. Connect a 0.1 $\mu$ F capacitor between $V_{CC}$ and GND as close as possible to the device.		
3	3	3	GND	Ground		
4	_	_	SAS	I <sup>2</sup> C Slave Address Selection Input		
_	4	4	CB0B	Switch Control Bit. See the switch control input table 1.		
5	_	_	ĪNT	Open-Drain Interrupt Output. INT asserts when interrupt happens.		
_	5	5	CB1B	Switch Control Bit. See the switch control input table 1.		
6	6	6	DPB	USB Connector D+ Connection		
7	7	7	DMB	USB Connector D- Connection		

# Dual-Channel USB Host Adapter Emulators

# **Pin Description (continued)**

	PIN		NAME	FUNCTION
MAX14657	MAX14658	MAX14659	NAIVIE	FUNCTION
8	8	_	CENB	Current-Limit Switch (CLS) Control Output. n-MOSFET open-drain pulldown output disables the CLS with active-high EN.
_	_	8	CENB	Current-Limit Switch (CLS) Control Output. p-MOSFET open-drain pullup output disables the CLS with active-low $\overline{\text{EN}}$ .
9	9	9	TDPB	Host USB Transceiver D+ Connection
10	10	10	TDMB	Host USB Transceiver D- Connection
11	11	11	TDMA	Host USB Transceiver D- Connection
12	12	12	TDPA	Host USB Transceiver D+ Connection
13	13	_	CENA	Current-Limit Switch (CLS) Control Output. n-MOSFET open-drain pulldown output disables the CLS with active-high EN.
_	_	13	CENA	Current-Limit Switch (CLS) Control Output. p-MOSFET open-drain pullup output disables the CLS with active-low $\overline{\text{EN}}$ .
14	14	14	DMA	USB Connector D- Connection
15	15	15	DPA	USB Connector D+ Connection
16			SCL	I <sup>2</sup> C Serial Clock
_	16	16	CB1A	Switch Control Bit. See the switch control input table 1.
_	_	_	EP	Exposed Pad. Connect EP to the ground plane.

# **Functional Diagram**



# **Dual-Channel USB Host Adapter Emulators**

### **Detailed Description**

The MAX14657/MAX14658/MAX14659 adaptor emulator devices have Hi-Speed USB analog switches that support USB hosts by identifying the USB port as a charger when the USB host is in a low-power mode and cannot enumerate USB devices. The devices feature low 4pF (typ) on-capacitance and low 3 $\Omega$  (typ) on-resistance when the USB switches are connected. DP\_ and DM\_ are capable of handling signals between 0V and 5.5V over the entire 3.0V to 5.5V supply range.

The MAX14657 are controlled by an I<sup>2</sup>C interface, while the MAX14658/MAX14659 are controlled by the CB0\_ and CB1\_ logic inputs. The I<sup>2</sup>C interface allows further customization over which mode the MAX14657 operates in, and can be used to read back connection information.

Improvements over the MAX14600 USB detector family include support for some smart phones that do not connect after applying 0.6V in charging downstream port (CDP) mode. The devices also support high-current charging of Apple devices while in sleep mode.

### **Enhanced Automode**

The ICs feature an enhanced automode (AM1, AM2) that allows full charging for Apple devices, USB-compliant devices, and Samsung Galaxy tablets.

#### **Resistor-Dividers**

The internal voltage buffers with series resistors emulate equivalent resistor-divider networks on the data lines to provide support for Apple/Samsung devices. The voltage buffers are disconnected while not in use to minimize the supply current. The voltage buffers are not connected in pass-through mode. Table 1 summarizes the equivalent resistor values connected to DP\_/DM\_ in different charging modes.

### **Switch Control**

### **Digital Controls**

Each channel of the MAX14658/MAX14659 features two digital select inputs, CB0\_ and CB1\_, for mode selection. Table 2 shows how the CB1\_/CB0\_ inputs can be used to enter Apple 2A auto-detection charger mode (AM2), pass-through mode (PM), forced charger mode (FM), and pass-through mode with CDP emulation (CM).

In CDP emulation mode, the peripheral device with CDP detection capability draws charging current up to 1.5A immediately without USB enumeration.

Table 1. DP /DM Resistor-Dividers

CHARGING MODE	DP_ PULLUP	DP_ PULLDOWN	DM_ PULLUP	DM_ PULLDOWN
AM1	75kΩ	49.9kΩ	43.2kΩ	49.9kΩ
AM2	43.2kΩ	49.9kΩ	75kΩ	49.9kΩ

Table 2. Digital Input State Table for MAX14658/MAX14659

CB1A/B	CB0A/B	CHARGER/USB	MODE	STATUS
0	0	CHARGER	AM2	2A Autodetection Charger Mode. For Apple, Samsung Galaxy tablets, and USB-compliant devices. Voltage buffers emulating Apple 2A resistor-dividers are connected to DP_/DM
0	1	USB	PM	USB Pass-Through Mode. DP_/DM_ are connected to TDP_/TDM
1	0	CHARGER	FM	Forced Dedicated Charger Mode. DP_ and DM_ are shorted.
1	1	USB	СМ	USB Pass-Through Mode with CDP Emulation. Autoconnects DP_/DM_ to TDM_/TDM_ depending on CDP detection status.

# **Dual-Channel USB Host Adapter Emulators**

### I<sup>2</sup>C Controls

The MAX14657 mode is controlled by the MODE\_SEL[2:0] bits. <u>Table 3</u> shows how these bits control the device. In addition to being configurable in all modes, the MAX14657 can be configured for the Apple (AP1 and AP2 modes), Samsung Galaxy (SS mode) devices, and Automodes (AM1 and AM2).

### **Legacy D+/D- Detect**

The devices support charging devices that use a D+/D-short to indicate it is ready for charging. This is done by monitoring the voltage at both the DP\_ and DM\_ terminals and triggering when they are both higher than their comparator thresholds.

### **Auto Peripheral Reset**

The MAX14658/MAX14659 feature an autocurrent limit switch control output. This feature resets the peripheral

connected to VBUS in the event the USB host switches to or from standby mode.  $\overline{\text{CEN}}$  or CEN\_ are pulsed for 1s (typ) on the rising or falling edge of CB0\_ or CB1\_ (Figure 5 and Figure 6).

### **Pass-Through Mode**

When the ICs are configured in pass-through mode (PM), TDP\_/TDM\_ are always connected to DP\_/DM\_ and no resistor-dividers or power sources are applied to DP\_/DM\_.

### **Forced Charger Modes**

The ICs can be configured in different forced dedicated charging port (DCP) modes; VBUS is enabled and DP\_ and DM\_ are shorted (FM mode) or connected to the voltage buffers emulating resistor-dividers (all other modes). Table 4 summarizes the equivalent resistor-divider values in each forced mode.

**Table 3. Digital Input State Table for MAX14657** 

MOD	E_SEL	_A/B	CHARGER/USB	MODE	STATUS		
[2]	[1]	[0]	CHARGER/03B	WODE	SIAIUS		
0	0	0	AUTOMODE CHARGER	AM2	2A Autodetection Charger Mode. For Apple, Samsung Galaxy tablets, and US compliant devices. Voltage buffers emulating Apple 2A resistor-dividers are connected to DP_/DM		
0	0	1	USB	PM	USB Pass-Through Mode. DP_/DM_ are connected to TDP_/TDM		
0	1	0	FORCED CHARGER	FM	Forced Dedicated Charger Mode. DP_ and DM_ are shorted.		
0	1	1	USB	СМ	USB Pass-Through Mode with CDP Emulation. Autoconnects DP_/DM_ to TDP_/TDM_ depending on CDP detection status.		
1	0	0	AUTOMODE CHARGER	AM1	1A Autodetection Charger Mode. For Apple, Samsung Galaxy tablets, and USB-compliant devices. Voltage buffers emulating Apple 1A resistor-dividers are connected to DP_/DM		
1	0	1	FORCED CHARGER	AP1	Forced 1A Charger Mode for Apple Devices. Voltage buffers emulating Apple 1A resistor-dividers are connected to DP_/DM		
1	1	0	FORCED CHARGER	AP2	Forced 2A Charger Mode for Apple Devices. Voltage buffers emulating Apple 2A resistor-dividers are connected to DP_/DM		
1	1	1	FORCED CHARGER	SS	Forced 2A Charger Mode for Samsung Galaxy Tablets. Voltage buffers emulating Samsung resistor-dividers are connected to DP_/DM_ and DP_ and DM_ are shorted.		

**Table 4. Forced Charging Modes** 

CHARGING MODE	DP_ PULLUP	DP_ PULLDOWN	DM_ PULLUP	DM_ PULLDOWN
FM	N/A	N/A	N/A	N/A
SS	30kΩ	10kΩ	30kΩ	10kΩ
AP1	75kΩ	49.9kΩ	43.2kΩ	49.9kΩ
AP2	43.2kΩ	49.9kΩ	75kΩ	49.9kΩ

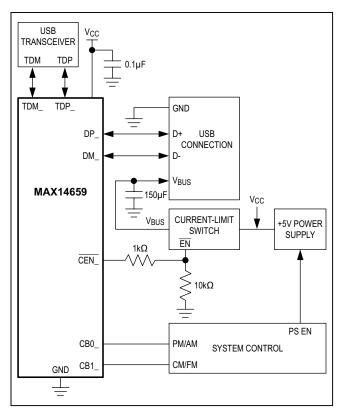


Figure 5. MAX14659 Peripheral Reset Applications Diagram (CEN is CEN for MAX14658)

Table 5. USB Host Power States

#### **STATE DESCRIPTION** S0 System On Power to the CPU(s) and RAM is maintained; S1 devices that do not indicate they must remain on may be powered down. CPU is Powered Off S2 Standby (Suspend to Ram): System memory S3 context is maintained, all other system context is lost. S4 Hibernate: Platform context is maintained. S5 Soft-Off

# Automatic Detection with Remote Wakeup Support

The devices feature automatic detection charger mode (AM1/AM2) for dedicated chargers and USB masters. In automatic detection charger mode, the device monitors

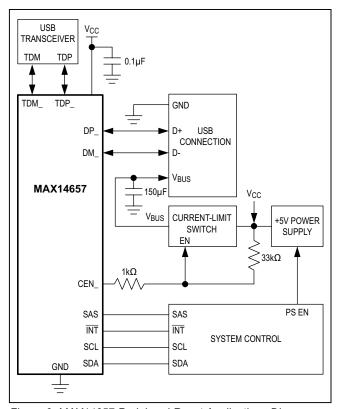


Figure 6. MAX14657 Peripheral Reset Applications Diagram

the voltages on DM\_ and DP\_ with voltage buffers connected to determine the type of device attached.

If a USB-compliant device is connected, DP\_ and DM\_ are shorted together to commence charging. Once the charging device is removed, the short between DP\_ and DM\_ is disconnected and the voltage buffer is applied. A pulldown resistor on the shorted DP\_/DM\_ node ensures that a disconnect is detected.

### **USB Pass-Through Mode with CDP Emulation**

The ICs feature a pass-through mode with CDP emulation (CM). This is to support the higher charging current capability during the pass-through mode in normal USB operation (S0 state). The peripheral device equipped with CDP detection capability can draw a charging current as defined in USB battery charger specification 1.2 when the charging host supports the CDP mode. This is a useful feature since most host USB transceivers do not have the CDP function. Table 5 summarizes the USB host power states.

**Table 6. Register Map/Register Descriptions** 

REGISTER	ADDR	TYPE	POR	BIT 7	BIT 6	BIT 5	BIT 4	BIT 3	BIT 2	BIT 1	BIT 0
DeviceID	0x00	R	0x11		CHIPIE	0[3:0]		CHIPREV[3:0]			
Control1	0x01	R/W	0xA7	FUO	FUO	FUO	FUO	FUO	FUO	FUO	FUO
Control2	0x02	R/W	0x50	LOW_PWR	FUO	FUO	FUO	FUO	FUO	DIS_CDP	FUO
Control3	0x03	R/W	0xE9	CEN_	CEN_CNT[1:0]		N_DEL[2:0]	MODE_SEL[2:0]		0]	
Control4	0x04	R/W	0x00	RFU	RFU	RFU	RFU	RFU	RFU	RFU	RFU
Control5	0x05	R/W	0x6B	INT_EN	USB_S	SW[1:0]	FUO	CEN_POL	FUO	RWU_DFT	RWU_LS
INT	0x06	R	0x00	CDP_DEVi	BYPASS_CDPi	CDP_CN_TMRi	RFU	USB_XFRi	RWUi	CEN_TOG_STi	CEN_TOG_SPi
STATUS	0x07	R	0x00	CDP_DEVs	BYPASS_CDPs	CDP_CN_TMRs	RFU	USB_XFRs	RWUs	RFU	CEN_TOG_Ss
MASK	0x08	R/W	0x00	CDP_DEVm	BYPASS_CDPm	CDP_CN_TMRm	RFU	USB_XFRm	RWUm	CEN_TOG_STm	CEN_TOG_SPm

FUO = Factory use only. Do not change from POR values.

RFU = Reserved for future use. Do not change from POR values.

# **Table 7. Device ID Register**

ADDRESS:		0x00								
MODE:		Read Only								
BIT	7	6	5	4	3	2	1	0		
NAME		CHIPI	D[3:0]		CHIPREV[3:0]					
RESET	0	0	0	1	0	0	0	1		
CHIPID[3:0]	The CHIPID[3	The CHIPID[3:0] bits show information about the version of the MAX14657.								
CHIPREV[3:0]	The CHIPRE\	The CHIPREV[3:0] bits show information about the revision of the MAX14657 silicon.								

# **Table 8. Control 1 Register**

ADDRES	SS:	0x01	0x01								
MODE: Read/Write											
BIT	7	6	6 5 4 3 2 1								
NAME	FUO	FUO	FUO FUO FUO FUO FUO FUO								
RESET	1	1 0 1 0 0 1 1 1									
FUO	Factory Use Only. Do not modify from reset values.										

# **Table 9. Control 2 Register**

ADDRESS:		0x02									
MODE:		Read/Write									
BIT	7	6	5	4	3	2	1	0			
NAME	LOW_PWR	FUO	FUO	FUO	FUO	FUO	DIS_CDP	FUO			
RESET	0	0 1 0 1 0 0 0									
LOW_PWR		57 is in normal o	•	cuitry other than	the I <sup>2</sup> C interface	e is disabled.					
DIS_CDP	0 = CDP sign	isable CDP Signal  = CDP signaling enabled  = CDP signaling disabled									
FUO	Factory Use	Only. Do not mo	dify from reset	values.							

# **Table 10. Control 3 Register**

ADDRESS:		0x03							
MODE:		Read/Write							
BIT	7	6	5	4	3	2	1	0	
NAME	CEN_CI	NT[1:0]	C	MODE_SEL[2:0]					
RESET	1	1	1	0	1	0	0	1	
CEN_CNT[1:0]	CEN_ State Control. Directly controls the CEN_ output independent of automatic cycling.  00 = CEN_ asserted  01 = FUO  10 = CEN_ deasserted (intend to turn on current-limit switch)  11 = CEN_ controlled by CDP/DCP/AM modes								
CEN_DEL[2:0]	CEN_ Pulse De 000 = 125ms 001 = 250ms 010 = 350ms 011 = 500ms 100 = 750ms 101 = 1.0s 110 = 1.5s 111 = 2s	elay. Controls ho	ow long V <sub>BUS</sub> tog	gles last outside	e of AM mode	Э.			
MODE_SEL[2:0]	Operating Mode 000 = AM2 001 = PM 010 = FM 011 = CM 100 = AM1 101 = AP1 110 = AP2 111 = SS	e Control.							

# **Table 11. Control 4 Register**

ADDRES	SS:	0x04	0x04								
MODE: Read/Write											
BIT	7	6	5	4	3	2	1	0			
NAME	RFU	RFU	RFU RFU RFU RFU RFU RFU								
RESET	0	0 0 0 0 0 0 0									
RFU	Reserved for Future Use										

# **Table 12. Control 5 Register**

ADDRESS:		0x05									
MODE:		Read/Write									
BIT	7	6	1	0							
NAME	INT_EN	USB_S	SW[1:0]	FUO	CEN_POL	FUO	RWU_DFT	RWU_LS			
RESET	0	0 1 1 0 1 0 1									
INT_EN	0 = Interrupt	Interrupt Enable.  0 = Interrupt disabled  1 = Interrupt enabled									
USB_SW[1:0]	CEN_ output 00 = DP_/DN 01 = DP_/DN 10 = DP_/DN	USB DPDT Switch Control. When the USB switch is forced open (00) or closed (01), the state machine and CEN_ output are disabled.  00 = DP_/DM_ in High-Z  01 = DP_/DM_ connected to TDP_/TDM_  10 = DP_/DM_ controlled by CDP/DCP/AM circuitry  11 = DP_/DM_ controlled by CDP/DCP/AM circuitry									
FUO	Factory Use	Only. Do not m	odify from rese	t value.							
CEN_POL	0 = CEN out	v Select. Contro put is active-lov put is active-hig	v CEN	of the CEN o	utput.						
FUO	Factory Use	Only. Do not m	odify from rese	t value.							
RWU_DFT	0 = Remote	Remote Wake-Up Default 0 = Remote wake-up is off 1 = Remote wake-up is on									
RWU_LS	Remote Wake-Up for Low-Speed Only Select  0 = Remote wake-up for both FS/HS and LS USB devices  1 = Remote wake-up for only LS devices										

**Table 13. Interrupt Register** 

ADDRESS:		0x06								
MODE:		Read Only								
BIT	7	6	5	4	3	2	1	0		
NAME	CDP_DEVi	BYPASS_CDPi	CDP_CNi	RFU	USB_XFRi	RWUi	CEN_TOG_STi	CEN_TOG_SPi		
RESET	0	0	0	0	0	0	0	0		
CDP_DEVi	CDP Device Detect Status Interrupt. CDP_DEVi is set when a CDP device is detected following the CDP handshake procedure in CM mode.  0 = No interrupt  1 = Interrupt									
BYPASS_CDPi	Bypass CDP Running Status Interrupt. BYPASS_CDPi is set when the CDP handshake procedure is bypassed.  0 = No interrupt  1 = Interrupt									
CDP_CNi		CDP Connect Status Interrupt. CDP_CNi is set whenever a CDP connection check is in progress.    = No interrupt   = Interrupt								
RFU	Reserved for F	Reserved for Future Use								
USB_XFRi	USB Session connected to 0 = No interrupt		Ri is set wher	there i	s USB data de	etected in	CM mode and DP	_/DM_ are		
RWUi	Remote Wake 0 = No interrup 1 = Interrupt	-Up Status Interrup ot	t. RWUi is se	t when	ever a remote	wake-up	is performed in AM	l mode.		
CEN_TOG_STi	disabled.	EN_ Toggle Start Monitor Interrupt. CEN_TOG_STi is set at the start of a V <sub>BUS</sub> toggle, when V <sub>BUS</sub> is first isabled.  = No interrupt								
CEN_TOG_SPi	disabled.	CEN_ Toggle Stop Monitor Interrupt. CEN_TOG_SPi is set at the end of a V <sub>BUS</sub> toggle, when V <sub>BUS</sub> is no longer disabled.  0 = No interrupt								

# **Table 14. Status Register**

ADDRESS:		0x07									
MODE:		Read Only									
BIT	7	6	5	4	3	2	1	0			
NAME	CDP_DEVs	BYPASS_CDPs	CDP_CNs	RFU	USB_XFRs	RWUs	RFU	CEN_TOGs			
RESET	0	0 0 0 0 0 0 0									
CDP_DEVs	procedure in 0 = CDP devi	CDP Device Detect Status. CDP_DEVs is set when a CDP device is detected following the CDP handshake procedure in CM mode and cleared when it is disconnected.  0 = CDP device not detected  1 = CDP device detected									
BYPASS_CDPs	Bypass CDP Running Status. BYPASS_CDPs is set when the CDP handshake procedure is bypassed.  0 = CDP signaling used  1 = CDP signaling bypassed										
CDP_CNs	CDP Connect Status. CDP_CNs is set while a CDP connection attempt is in progress.  0 = No CDP connection check in progress  1 = CDP connection check in progress										
RFU	Reserved for	Future Use									
USB_XFRs	connected to 0 = No USB s	Status. USB_XFRs i TDP/TDM. ession in progress ion in progress	s set while the	ere is US	B data detected	l in CM mod	e and DP_/	DM_ are			
RWUs	0 = Not waitin	Remote Wake-Up Status. RWUs is set while a remote wake-up is in progress in AM mode.  0 = Not waiting for RWU  1 = Waiting for RWU									
CEN_TOGs	CEN_ Toggle Status. CEN_TOGs is cleared at the start of a $V_{BUS}$ toggle and set at the end of the $V_{BUS}$ toggle. $0 = V_{BUS}$ toggle in progress $1 = V_{BUS}$ toggle not in progress										

**Table 15. Mask Register** 

ADDRESS:		0x08									
MODE:	,	Read/Write									
BIT	7	6	5	4	3	2	1	0			
NAME	CDP_ DEVm	BYPASS_ CDPm	CDP_CNm	RFU	USB_XFRm	RWUm	CEN_TOG_ STm	CEN_TOG_ SPm			
RESET	0	0	0	0	0	0	0	0			
CDP_DEVm			nterrupt Mask. F	Prevents a	an interrupt from b	peing gener	rated in CDP_DI	EVi when			
BYPASS_CDPm	when BY 0 = Mask	Bypass CDP Running Status Interrupt Mask. Prevents an interrupt from being generated in BYPASS_CDPi when BYPASS_CDPs is set to 1.  0 = Masked  1 = Not masked									
CDP_CNm	CDP Connect Status Interrupt Mask. Prevents an interrupt from being generated in CDP_CNi when CDP_CNs is set to 1.  0 = Masked 1 = Not masked										
RFU	Reserve	d for Future Use									
USB_XFRm	USB Ses set to 1. 0 = Mask 1 = Not r		k. Prevents an i	interrupt t	from being gener	ated in USI	3_XFRi when U	ISB_XFRs is			
RWUm	Remote set to 1. 0 = Mask 1 = Not r		iterrupt Mask. P	revents a	n interrupt from I	peing gene	rated in RWUi v	vhen RWUs is			
CEN_TOG_STm	when CE 0 = Mask	CEN_ Toggle Start Monitor Interrupt Mask. Prevents an interrupt from being generated in CEN_TOG_STi when CEN_TOG_STs is set to 1.  D = Masked  1 = Not masked									
CEN_TOG_SPm	when CE 0 = Mask	CEN_ Toggle Stop Monitor Interrupt Mask. Prevents an interrupt from being generated in CEN_TOG_SPi when CEN_TOG_SPs is set to 1.  0 = Masked 1 = Not masked									

### **Applications Information**

### I<sup>2</sup>C Interface

The MAX14657 contain an I<sup>2</sup>C-compatible interface for data communication with a host controller (SCL and SDA). The interface supports a clock frequency of up to 400kHz. SCL and SDA require pullup resistors that are connected to a positive supply.

### Start, Stop, and Repeated Start Conditions

When writing to the MAX14657 using I<sup>2</sup>C, the master sends a START condition (S) followed by the MAX14657 I<sup>2</sup>C address. After the address, the master sends the register address of the register that is to be programmed. The master then ends communication by issuing a STOP condition (P) to relinquish control of the bus, or a Repeated START condition (Sr) to communicate to another I<sup>2</sup>C slave. See Figure 7.

### **Slave Address**

The MAX14657 is the I<sup>2</sup>C version that has different slave addresses for each port (<u>Table 16</u>). Set the Read/Write bit high to configure the MAX14657 to read mode. Set the Read/Write bit low to configure the MAX14657 to write mode. Further, two possible slave addresses can be configured for each port through the Slave Address Selection (SAS) input (see <u>Table 16</u>), allowing up to two MAX14657 devices to share the same interface bus. The address is the first byte of information sent to the MAX14657 after the START condition.

#### **Bit Transfer**

One data bit is transferred on the rising edge of each SCL clock cycle. The data on SDA must remain stable during the high period of the SCL clock pulse. Changes in SDA while SCL is high and stable are considered control signals (see the <u>Start, Stop, and Repeated Start Conditions</u> section). Both SDA and SCL remain high when the bus is not active.

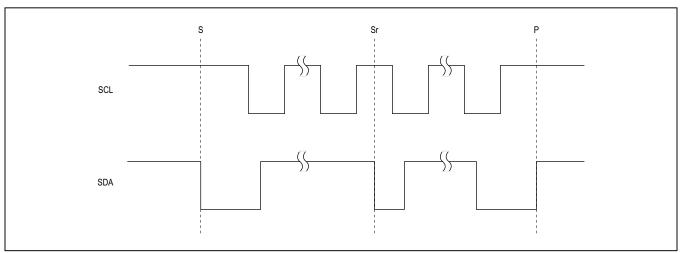


Figure 7. I<sup>2</sup>C START, STOP, and REPEATED START Conditions

### Table 16. MAX14657 I<sup>2</sup>C Slave Addresses

SAS	Port	A6	A5	A4	А3	A2	<b>A</b> 1	A0	R/W	READ ADDR	WRITE ADDR
CND	Α	0	1	0	0	1	0	0	1/0	0x49	0x48
GND	В	0	1	0	1	1	0	0	1/0	0x59	0x58
V	Α	0	1	0	0	1	0	1	1/0	0x4B	0x4A
V <sub>CC</sub>	В	0	1	0	1	1	0	1	1/0	0x5B	0x5A

# **Dual-Channel USB Host Adapter Emulators**

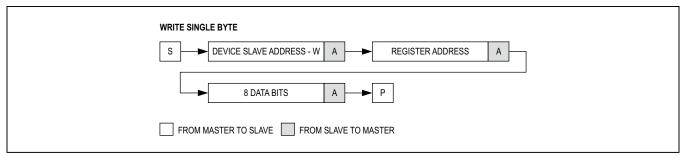


Figure 8. Write Byte Sequence

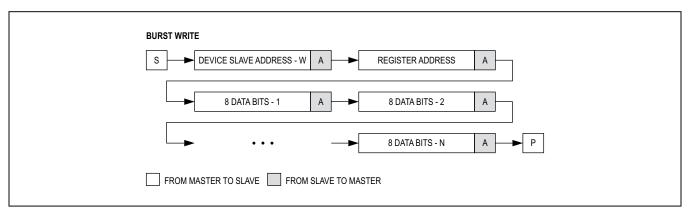


Figure 9. Burst Write Sequence

### **Single Byte Write**

In this operation, the master sends an address and two data bytes to the slave device (Figure 8). The following procedure describes the single byte write operation:

- 1) The master sends a START condition
- 2) The master sends the 7-bit slave address plus a write bit (low)
- 3) The addressed slave asserts an ACK on the data line
- 4) The master sends the 8-bit register address
- 5) The slave asserts an ACK on the data line only if the address is valid (NAK if not)
- 6) The master sends 8 data bits
- 7) The slave asserts an ACK on the data line
- 8) The master generates a STOP condition

### **Burst Write**

In this operation, the master sends an address and multiple data bytes to the slave device (Figure 9). The slave device automatically increments the register address after each data byte is sent, unless the register being accessed is 0x00, in which case the register address remains the same. The following procedure describes the burst write operation:

- 1) The master sends a START condition
- 2) The master sends the 7-bit slave address plus a write bit (low)
- 3) The addressed slave asserts an ACK on the data line
- 4) The master sends the 8-bit register address
- 5) The slave asserts an ACK on the data line only if the address is valid (NAK if not)
- 6) The master sends 8 data bits
- 7) The slave asserts an ACK on the data line
- 8) Repeat 6 and 7 (N-1) times
- 9) The master generates a STOP condition

# **Dual-Channel USB Host Adapter Emulators**

### Single Byte Read

In this operation, the master sends an address plus two data bytes and receives one data byte from the slave device (<u>Figure 10</u>). The following procedure describes the single byte read operation:

- 1) The master sends a START condition
- The master sends the 7-bit slave address plus a write bit (low)
- 3) The addressed slave asserts an ACK on the data line
- 4) The master sends the 8-bit register address
- 5) The slave asserts an ACK on the data line only if the address is valid (NAK if not)
- 6) The master sends a REPEATED START condition
- 7) The master sends the 7-bit slave address plus a read bit (high)
- 8) The addressed slave asserts an ACK on the data line
- 9) The slave sends 8 data bits

- 10) The master asserts a NACK on the data line
- 11) The master generates a STOP condition

#### **Burst Read**

In this operation, the master sends an address plus two data bytes and receives multiple data bytes from the slave device (<u>Figure 11</u>). The following procedure describes the burst byte read operation:

- 1) The master sends a START condition
- The master sends the 7-bit slave address plus a write bit (low)
- 3) The addressed slave asserts an ACK on the data line
- The master sends the 8-bit register address
- 5) The slave asserts an ACK on the data line only if the address is valid (NAK if not)
- 6) The master sends a REPEATED START condition
- 7) The master sends the 7-bit slave address plus a read bit (high)

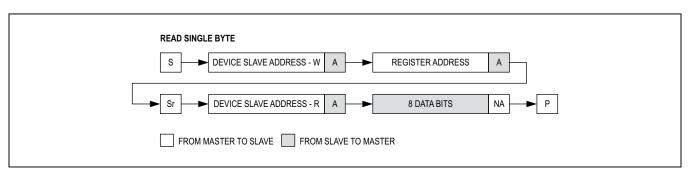


Figure 10. Read Byte Sequence

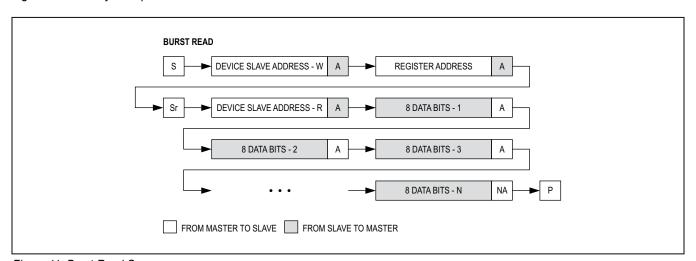


Figure 11. Burst Read Sequence

# **Dual-Channel USB Host Adapter Emulators**

- 8) The slave asserts an ACK on the data line
- 9) The slave sends 8 data bits
- 10) The master asserts an ACK on the data line
- 11) Repeat 9 and 10 (N-2) times
- 12) The slave sends the last 8 data bits
- 13) The master asserts a NACK on the data line
- 14) The master generates a STOP condition

### **Acknowledge Bits**

Data transfers are acknowledged with an acknowledge bit (ACK) or a not-acknowledge bit (NACK). Both the master and the MAX14657 generate ACK bits. To generate an ACK, pull SDA low before the rising edge of the ninth clock pulse and hold it low during the high period of the ninth clock pulse (see Figure 12). To generate a NACK,

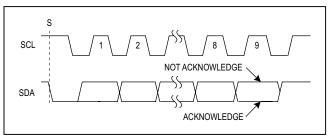


Figure 12. Acknowledge

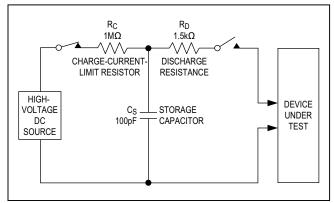


Figure 13. Human Body ESD Test Model

leave SDA high before the rising edge of the ninth clock pulse and leave it high for the duration of the ninth clock pulse. Monitoring for NACK bits allows for detection of unsuccessful data transfers.

### **High ESD Protection**

Electrostatic discharge (ESD) protection structures are incorporated on all pins to protect against electrostatic discharges up to ±2kV Human Body Model (HBM) encountered during handling and assembly. DP\_ and DM\_ are further protected against high ESD up to ±15kV (HBM) without damage. These ESD structures withstand high ESD both in normal operation and when the device is powered down. After an ESD event, the IC continues to function without latchup.

### **ESD Test Conditions**

ESD performance depends on a variety of conditions. Contact Maxim for a reliability report that documents test setup, test methodology, and test results.

### **Human Body Model**

<u>Figure 13</u> shows the Human Body Model. <u>Figure 14</u> shows the current waveform it generates when discharged into a low impedance. This model consists of a 100pF capacitor charged to the ESD voltage of interest that is then discharged into the device through a  $1.5k\Omega$  resistor.

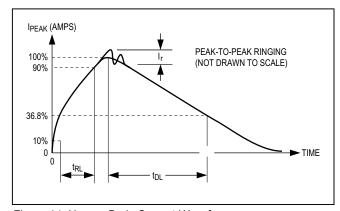


Figure 14. Human Body Current Waveform